

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/522,036	MARUYAMA ET AL.	
Examiner	Art Unit	
Sin J. Lee	1752	

SEARCHED					
Class	Subclass	Date	Examiner		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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430/270.1 Search in EAST (TEXT Search 0114) - Dee Search History Prontout	10-2 -0 5	SJL	
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